

# NDH8301N

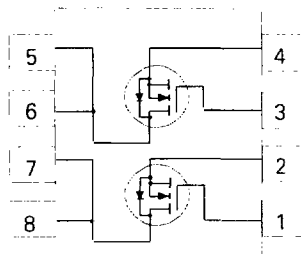
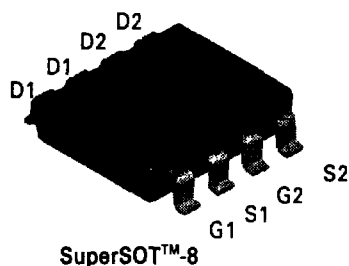
## Dual N-Channel Enhancement Mode Field Effect Transistor

### General Description

These N-Channel enhancement mode power field effect transistors are produced using Nationals proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where fast switching, and low in-line power loss are needed in a very small outline surface mount package.

### Features

- 3A, 30V.  $R_{DS(ON)} = 0.06\Omega$  @  $V_{GS} = 4.5V$   
 $R_{DS(ON)} = 0.075\Omega$  @  $V_{GS} = 2.7V$ .
- Proprietary SuperSOT™-8 package design using copper lead frame for superior thermal and electrical capabilities.
- High density cell design for extremely low  $R_{DS(ON)}$ .
- Exceptional on-resistance and maximum DC current capability.



### Absolute Maximum Ratings $T_A = 25^\circ C$ unless otherwise noted

Symbol	Parameter	NDH8301N	Units
$V_{DS}$	Drain-Source Voltage	20	V
$V_{GS}$	Gate-Source Voltage	8	V
$I_D$	Drain Current - Continuous (Note 1)	3	A
	- Pulsed	9	
$P_D$	Maximum Power Dissipation (Note 1)	0.9	W
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to 150	$^\circ C$

### THERMAL CHARACTERISTICS

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	135	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)	40	$^\circ C/W$

# **ELECTRICAL CHARACTERISTICS** ( $T_A = 25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>OFF CHARACTERISTICS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	20			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 16\text{ V}, V_{GS} = 0\text{ V}$			1	$\mu\text{A}$
		$T_J = 55^{\circ}\text{C}$			10	$\mu\text{A}$
$I_{GSSF}$	Gate - Body Leakage, Forward	$V_{GS} = 8\text{ V}, V_{DS} = 0\text{ V}$			100	nA
$I_{GSSR}$	Gate - Body Leakage, Reverse	$V_{GS} = -8\text{ V}, V_{DS} = 0\text{ V}$			-100	nA

## **ON CHARACTERISTICS** (Note 2)

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	0.4		1	V
		$T_J = 125^{\circ}\text{C}$	0.3		0.8	
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS} = 4.5\text{ V}, I_D = 3\text{ A}$			0.06	$\Omega$
		$T_J = 125^{\circ}\text{C}$			0.11	
		$V_{GS} = 2.7\text{ V}, I_D = 2.7\text{ A}$			0.075	
$I_{D(on)}$	On-State Drain Current	$V_{GS} = 4.5\text{ V}, V_{DS} = 5\text{ V}$	9			A
		$V_{GS} = 2.7\text{ V}, V_{DS} = 5\text{ V}$	3			

## **DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS**

$I_S$	Maximum Continuous Drain-Source Diode Forward Current				0.75	A
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = 0.75\text{ A}$ (Note 2)			1.2	V

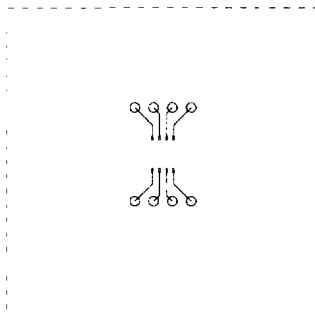
Notes:

- $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.

$$P_D(t) = \frac{T_J - T_A}{R_{\theta JA}(t)} = \frac{T_J - T_A}{R_{\theta JC} + R_{\theta CA}(t)} = P_D^2(t) \times R_{DS(ON)}@T_J$$

Typical  $R_{\theta JA}$  using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

135°C/W when mounted on a 0.0025in<sup>2</sup> pad of 2oz copper.



Scale 1 : 1 on letter size paper

- Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2.0\%$ .